



VOL. 276 No. 1 (2008)

International Journal of

Mass Spectrometry

Editors

S.A. McLuckey
West Lafayette, IN

H. Schwarz
Berlin

Special Issue
Consultant

M.T. Bowers
Santa Barbara, CA

Editorial Board

P.B. Armentrout
Salt Lake City, UT

T. Baer
Chapel Hill, NC

J.S. Becker
Jülich

V.M. Bierbaum
Boulder, CO

D.K. Böhme
North York, Ont.

B. Chait
New York, NY

D.E. Clemmer
Bloomington, IN

R.G. Cooks
West Lafayette, IN

M.L. Gross
St. Louis, MO

J. Grotemeyer
Kiel

A.J.R. Heck
Utrecht

R.M.A. Heeren
Amsterdam

G. von Helden
Berlin

F. Hillenkamp
Münster

J.A. Leary
Davis, CA

C.B. Lebrilla
Davis, CA

S. Liu
Changchun

R.E. March
Peterborough, Ont.

T.D. Märk
Innsbruck

A.G. Marshall
Tallahassee, FL

T.B. McMahon
Waterloo, Ont.

N.M.M. Nibbering
Amsterdam

R.A.J. O'Hair
Victoria

G. Ohanessian
Palaiseau

J.M. Riveros
São Paulo

C. Robinson
Cambridge

M.T. Rodgers
Detroit, MI

C.A. Schalley
Bonn

J. Scrivens
Middlesborough

R. Smith
Richland, WA

M. Speranza
Rome

F. Tureček
Seattle, WA

E. Uggerud
Blindern

E.R. Williams
Berkeley, CA

H. Wollnik
Giessen

V.H. Wysocki
Tucson, AZ

R.A. Yost
Gainesville, FL

R. Zenobi
Zurich

R. Zubarev
Uppsala



ELSEVIER

Amsterdam • Boston • Jena •
London • New York • Oxford •
Paris • Philadelphia •
San Diego • St. Louis